

Report No. : EED32I003158 Page 1 of 26



# **EMC TEST REPORT**

**Product** : AHD car camera

Trade mark : LINTECH

**Model/Type reference**: LC-012A,LC-012W, LC-012AT2,

LC-028A, LC-018A, LC-018B, LC-018C, LC-018D, LC-018E LC-007A, LC-009D1, LC-010G, LC-10A, LC-10B, LC-10C, LC-024A, LC-015DB, LC-009A, LC-009B,

LC-009C, LC-009D, LC-009E

Serial Number : N/A

Ratings : DC 12V

 Report Number
 : EED32I003158

 Date
 : Dec. 29, 2016

**Regulations** : See below

Test Standards	Results
⊠ EN 50498: 2010	PASS

## Prepared for:

# LINTECH ENTERPRISES LIMITED 3/F, Blcok A8, Kaida Creative Industry Park, Qiaochang Road, Qiaotou

3/F, Blcok A8, Kaida Creative Industry Park, Qiaochang Road, Qiaotou Town, Dongguan City, Guangdong, China

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Date:

Dec. 29, 2016

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Check No.: 2457573957





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(Note: N/A means not applicable)





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## 1. GENERAL INFORMATION

Applicant: LINTECH ENTERPRISES LIMITED

3/F, Blcok A8, Kaida Creative Industry Park, Qiaochang Road,

Qiaotou Town, Dongguan City, Guangdong, China

Manufacturer: LINTECH ENTERPRISES LIMITED

3/F, Blcok A8, Kaida Creative Industry Park, Qiaochang Road,

Qiaotou Town, Dongguan City, Guangdong, China

**EMC Directive:** 2014/30/EU

**Product:** AHD car camera

Trade mark: LINTECH

Model/Type reference: LC-012A,LC-012W, LC-012AT2, LC-028A, LC-018A,

LC-018B, LC-018C, LC-018D, LC-018E, LC-007A, LC-009D1, LC-010G, LC-10A, LC-10B, LC-10C, LC-024A, LC-015DB,

LC-009A, LC-009B, LC-009C, LC-009D, LC-009E

Serial Number: N/A

Report Number: EED32I003158
Sample Received Date: Oct. 26, 2016

Sample tested Date: Oct. 26, 2016 to Nov. 17, 2016

The tested sample(s) and the sample information are provided by the client. All test data come from the report of No. EED32I002788

## 2. TEST SUMMARY

The Product has been tested according to the following specifications:

Test Item (Test method is refer to 2014/30/EU directive)	Test Result	
Broadband Radiated Disturbances and Narrowband Radiated Disturbance	Pass	
Conducted Transient Disturbances	Pass	
Conducted Transient Immunity	Pass	

## 3. TEST UNCERTAINTY

Where relevant, the following test uncertainty levels have been estimated for tests performed on the Product as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Test item	Value (dB)
Radiated disturbance (30MHz to 1GHz)	5.3



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# 4. PRODUCT INFORMATION AND TEST SETUP

# 4.1 PRODUCT INFORMATION

Ratings: DC 12V

Model difference: All models are identical except the model name. The test model is

LC-012A and the test results are applicable to the others.

## 4.2 TEST SETUP CONFIGURATION

See test photographs attached in Appendix 1 for the actual connections between Product and support equipment.

#### 4.3 SUPPORT EQUIPMENT

	No.	Device Type Brand		rice Type Brand Model Series No.		Data Cable	Power Cord
26.00	1.	MORNITOR	LINTECH	LM-070C2AHD		( <del>5</del>	/

#### Notes:

- 1. All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.
- 2. Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.

# 5. FACILITIES AND ACCREDITATIONS

#### 5.1 TEST FACILITY

All test facilities used to collect the test data are located at Hongwei Industrial Zone, 70 Area, Bao'an District, Shenzhen, Guangdong, China. The site and apparatus are constructed in conformance with the requirements of ANSI C63.4, CISPR 16-1-1 and other equivalent standards.

#### 5.2 TEST EQUIPMENT LIST

**Instrumentation:** The following list contains equipments used at CTI for testing. The calibrations of the measuring instruments, including any accessories that many accessorie

The calibrations of the measuring instruments, including any accessories that may effect such calibration, are checked frequently to assure their accuracy. Adjustments are made and correction factors applied in accordance with instructions contained in the manual for the measuring instrument.

# Equipment used during the tests:

3M Semi-anechoic Chamber (2)-Broadband Radiated Disturbances and Narrowband Radiated Disturbance									
Equipment Manufacturer Model Serial No. Due Date									
3M Chamber & Accessory Equipment	TDK	SAC-3		06/01/2019					
Receiver	R&S	ESCI	100435	06/15/2017					
Multi device Controller	maturo NCD/070/10 112			N/A					
LISN	schwarzbeck	NNBM8125	81251547	06/15/2017					
LISN	schwarzbeck	NNBM8125	81251546	06/15/2017					
Log-periodic Antenna	schwarzbeck	VUSLP 9111B	9111B-088	03/19/2017					









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Biconical Antenna	schwarzbeck	VHBB 9124 + BBA 9106	9124-587	03/19/2017
Multi device Controller	Multi device Controller maturo			N/A
Microwave Preamplifier	Agilent	8449B	3008A02425	02/17/2017

Conducted Transient Disturbances Test						
Equipment Manufacturer Model Serial No. Due Dat						
ISO7637 Test System	TESEQ	NSG5500/5600	104	01/27/2017		

Conducted Transient Immunity Test							
Equipment Manufacturer Model Serial No. Due Date							
ISO7637 Test System	TESEQ	NSG5500/5600	W124	01/27/2017			

## 5.3 LABORATORY ACCREDITATIONS AND LISTINGS

The measuring equipment utilized to perform the tests documented in this report has been calibrated once a year or in accordance with the manufacturer's recommendations, and is traceable under the ISO/IEC/EN 17025 to international or national standards. Equipment has been calibrated by accredited calibration laboratories.







# **BROADBAND RADIATED DISTURBANCES AND** NARROWBAND RADIATED DISTURBANCES

## **TEST CONDITION**

**Operation mode** Normal **Test voltage DC 12V Test Condition** Temp: 24°C

> Related Humidity: 50% Air pressure: 101Kpa

Model/Type reference LC-012A

# 6.2 LIMITS

Frequency (MHz)	Broadband limits at 1m dΒ(μV/m)
30-75	62-52 <sup>a</sup>
75-400	52-63 b
400-1000	63

<sup>&</sup>lt;sup>a</sup> Decreasing linearly with the log of the frequency.

<sup>&</sup>lt;sup>b</sup> Increasing linearly with the log of the frequency.

Frequency (MHz)	Narrowband Limits at 1m dB(µV/m)			
30-75	52-42 a			
75-400	42-53 b	6		
400-1000	53			
<sup>a</sup> Decreasing linearly	with the log of the frequency.			

NOTE: The lower limit shall apply at the transition frequencies.



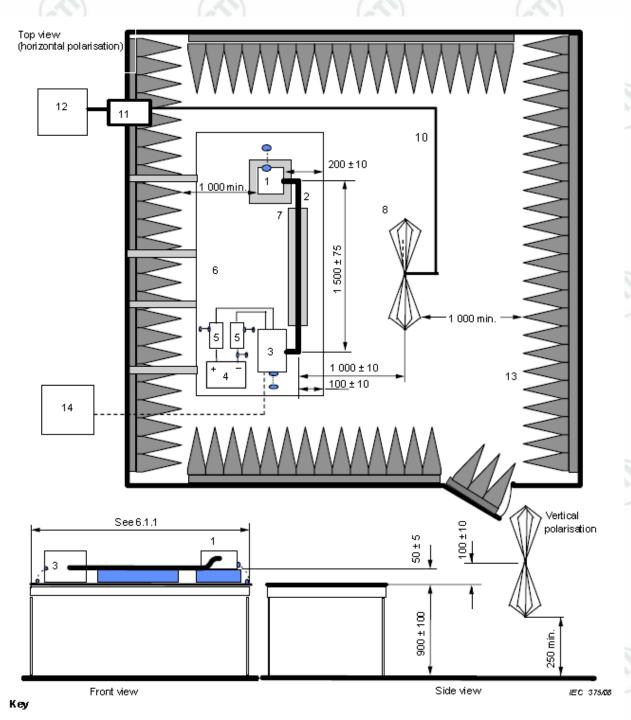
Hotline: 400-6788-333 E-mail: info@cti-cert.com www.cti-cert.com

<sup>&</sup>lt;sup>b</sup> Increasing linearly with the log of the frequency.





## 6.3 BLOCK DIAGRAM OF TEST SETUP



- EUT (grounded locally if required in test plan)
- 2 Test harness
- Load simulator (placement and ground connection 10 High-quality coaxial cable e.g. double-shielded (50  $\Omega$ ) according to 6.4.2.5)
- Power supply (location optional)
- 5 Artificial network (AN)
- Ground plane (bonded to shielded enclosure)
- Low relative permittivity support (ε<sub>r</sub> ≤ 1,4)

- 8 Biconical antenna
- 11 Bulkhead connector
- 12 Measuring instrument
- 13 RF absorber material
- 14 Stimulation and monitoring system





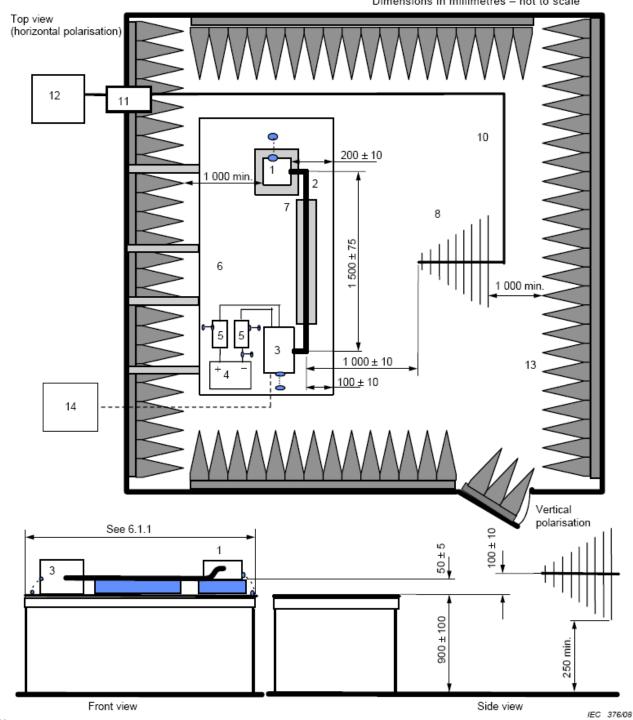




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Dimensions in millimetres - not to scale

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## Key

- EUT (grounded locally if required in test plan)
- Test harness
- 3 Load simulator (placement and ground connection 10 High-quality coaxial cable e.g. double-shielded (50 Ω) according to 6.4.2.5)
- Power supply (location optional)
- Artificial network (AN)
- Ground plane (bonded to shielded enclosure)
- Low relative permittivity support ( $\epsilon_r \leq 1,4$ )

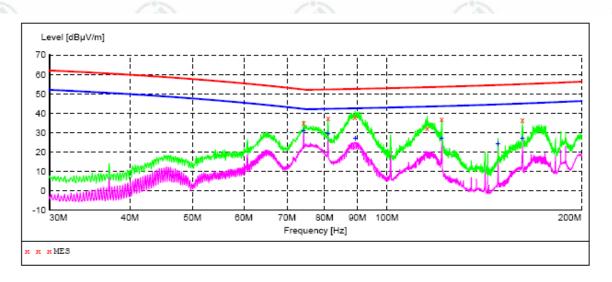
- Log-periodic antenna
- 11 Bulkhead connector
- 12 Measuring instrument
- 13 RF absorber material
- 14 Stimulation and monitoring system





## 6.4 TEST RESULT

Frequency : 30MHz-200MHz



#### MEASUREMENT RESULT:

Frequency MHz	Level dBµV/m		Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarization
74.280000 81.000000 89.160000 115.320000 121.500000	35.30 37.30 37.80 32.00 37.10 36.70	-22.6 -22.7 -22.5 -21.3 -20.9 -18.5	52.2 52.2 52.5 53.4 53.6 54.9	16.9 14.9 14.7 21.4 16.5 18.2	QP QP QP QP	0.0 0.0 0.0 0.0 0.0	0.00 0.00 0.00	HORIZONTAL HORIZONTAL HORIZONTAL HORIZONTAL HORIZONTAL HORIZONTAL

Frequency MHz	Level dBµV/m		Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarization
74.280000	30.60	-22.6	42.2	11.6	AV	0.0	0.00	HORIZONTAL
81.000000	29.20	-22.7	42.2	13.0	AV	0.0	0.00	HORIZONTAL
89.280000	26.80	-22.5	42.5	15.7	AV	0.0	0.00	HORIZONTAL
121.500000	27.00	-20.9	43.6	16.6	AV	0.0	0.00	HORIZONTAL
148.500000	24.20	-19.2	44.5	20.3	AV	0.0	0.00	HORIZONTAL
162.000000	27.10	-18.5	44.9	17.8	AV	0.0	0.00	HORIZONTAL













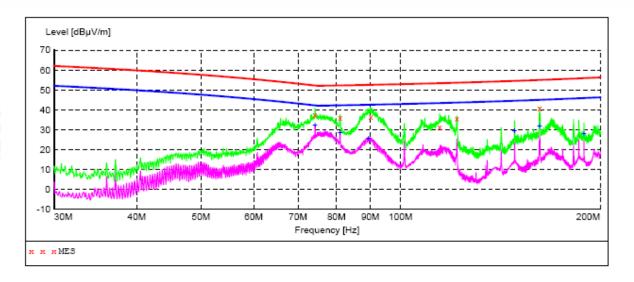






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#### MEASUREMENT RESULT:

Frequency MHz	Level dBµV/m		Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarization
74.220000	37.60	-22.6	52.2	14.6	QP	0.0	0.00	VERTICAL
81.000000	35.90	-22.7	52.2	16.3	QP	0.0	0.00	VERTICAL
90.120000	36.30	-22.5	52.5	16.2	QP	0.0	0.00	VERTICAL
114.480000	31.40	-21.4	53.3	21.9	QP	0.0	0.00	VERTICAL
121.560000	35.70	-20.9	53.6	17.9	QP	0.0	0.00	VERTICAL
162.000000	40.80	-18.5	54.9	14.1	QP	0.0	0.00	VERTICAL

Frequency MHz	Level dBµV/m		Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarization
74.280000	32.00	-22.6	42.2	10.2	AV	0.0	0.00	VERTICAL
81.000000	28.50	-22.7	42.2	13.7	AV	0.0	0.00	VERTICAL
89.400000	25.50	-22.5	42.5	17.0	AV	0.0	0.00	VERTICAL
148.500000	29.60	-19.2	44.5	14.9	AV	0.0	0.00	VERTICAL
162.000000	31.90	-18.5	44.9	13.0	AV	0.0	0.00	VERTICAL
189.000000	28.00	-17.1	45.9	17.9	AV	0.0	0.00	VERTICAL































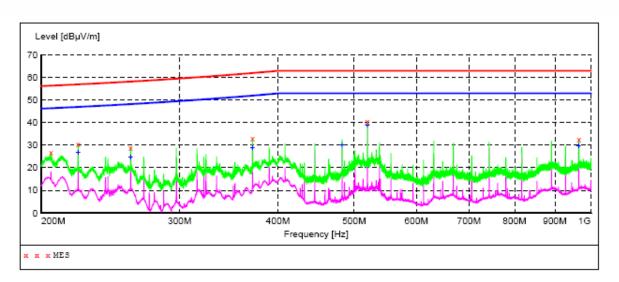


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Product : AHD car camera Model/Type
Power : DC 12V Mode

Frequency: 200MHz-1GHz

Model/Type reference : LC-012A Mode : Normal



#### MEASUREMENT RESULT:

Frequency MHz	Level dBµV/m		Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarization
205.700000	26.80	-17.1	56.4	29.6	QP	0.0	0.00	HORIZONTAL
222.740000	30.50	-16.9	57.0	26.5	QP	0.0	0.00	HORIZONTAL
259.880000	29.10	-16.2	58.3	29.2	QP	0.0	0.00	HORIZONTAL
371.240000	33.20	-13.0	62.0	28.8	QP	0.0	0.00	HORIZONTAL
519.740000	40.70	-11.3	63.0	22.3	QP	0.0	0.00	HORIZONTAL
965.240000	32.50	-3.1	63.0	30.5	QP	0.0	0.00	HORIZONTAL

Frequency MHz	Level dBµV/m		Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarization
222.740000	27.00	-16.9	47.0	20.0	AV	0.0	0.00	HORIZONTAL
259.880000	24.60	-16.2	48.3	23.7	AV	0.0	0.00	HORIZONTAL
371.240000	28.70	-13.0	52.0	23.3	AV	0.0	0.00	HORIZONTAL
482.600000	30.10	-11.9	53.0	22.9	AV	0.0	0.00	HORIZONTAL
519.740000	39.00	-11.3	53.0	14.0	AV	0.0	0.00	HORIZONTAL
965.240000	29.80	-3.1	53.0	23.2	AV	0.0	0.00	HORIZONTAL





















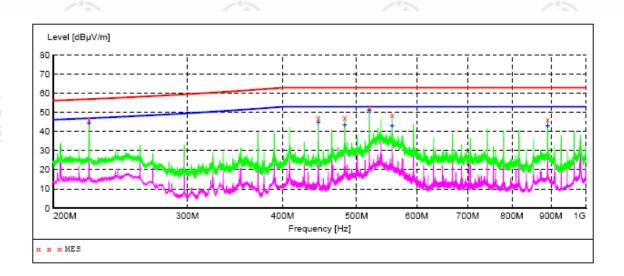






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#### MEASUREMENT RESULT:

Frequency MHz	Level dBµV/m	Transd dB	Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarization
222.740000	46.80	-16.9	57.0	10.2	QP	0.0	0.00	VERTICAL
445.520000	47.30	-12.7	63.0	15.7	QP	0.0	0.00	VERTICAL
482.600000	47.30	-11.9	63.0	15.7	QP	0.0	0.00	VERTICAL
519.740000	53.10	-11.3	63.0	9.9	QP	0.0	0.00	VERTICAL
556.880000	48.50	-10.9	63.0	14.5	QP	0.0	0.00	VERTICAL
891.020000	46.40	-4.4	63.0	16.6	QΡ	0.0	0.00	VERTICAL

Frequency MHz	Level dBµV/m	Transd dB	Limit dBµV/m	Margin dB	Det.	Height cm	Azimuth deg	Polarization
222.740000	44.30	-16.9	47.0	2.7	AV	0.0	0.00	VERTICAL
445.520000	44.90	-12.7	53.0	8.1	AV	0.0	0.00	VERTICAL
482.600000	43.50	-11.9	53.0	9.5	AV	0.0	0.00	VERTICAL
519.740000	51.30	-11.3	53.0	1.7	AV	0.0	0.00	VERTICAL
556.880000	42.80	-10.9	53.0	10.2	AV	0.0	0.00	VERTICAL
891.020000	43.10	-4.4	53.0	9.9	AV	0.0	0.00	VERTICAL

























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# 7. CONDUCTED TRANSIENT DISTURBANCES

## 7.1 TEST CONDITION

**Operation mode** : Normal **Test voltage** : DC 12V

**Test Condition** : Temp: 24℃

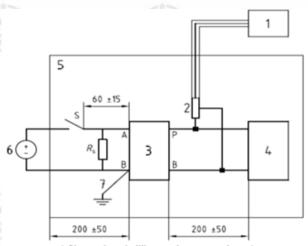
Related Humidity: 50% Air pressure: 101Kpa

Model/Type reference : LC-012A

## 7.2 LIMITS

Polarity of pulse	Maximum allowed pulse amplitude for						
amplitude	Vehicles with 12V systems	Vehicles with 24V systems					
Positive	+75	+150					
Negative	-100	-450					

## 7.3 BLOCK DIAGRAM OF TEST SETUP



a) Slow pulses (millisecond range or slower)

# 5 100 ±25 8 3 B 200 ±50

b) Fast pulses (nanosecond-to-micros-econd range)

#### Key

- oscilloscope or equivalent
- 2 voltage probe
- 3 artificial network
- 4 DUT (source of transient)

- 5 ground plane
- 6 power supply
- 7 Ground connection; length < 100 mm













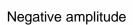


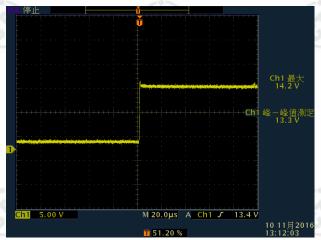
# 7.4 TEST RESULT

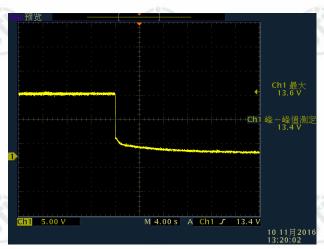
# Input DC 12V(Fast pulses)

Positive amplitude







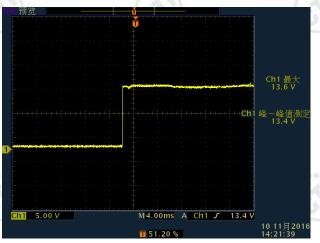


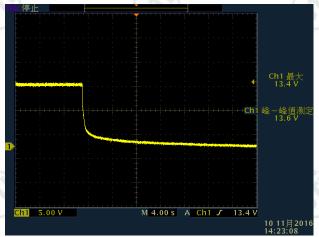
Polarity of pulse amplitude	Maximum allowed pulse amplitude	Maximum level	result
Positive	+75V	+14.2V	Pass
negative	-100V	-13.4V	Pass

# Input DC 12V(Slow pulses)

Positive amplitude

# Negative amplitude





Polarity of pulse amplitude	Maximum allowed pulse amplitude	Maximum level	result
Positive	+75V	+13.6V	Pass
negative	-100V	-13.6V	Pass















# 8. CONDUCTED TRANSIENT IMMUNITY

## 8.1 TEST CONDITION

Operation mode : Normal : DC 12V

Test Condition : Temp: 24℃

Related Humidity: 50% Air pressure: 101Kpa

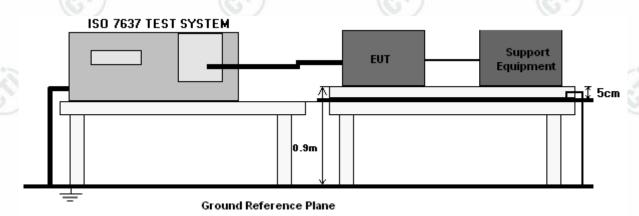
Model/Type reference : LC-012A

## 8.2 TEST LEVELS AND FUNCTIONAL STATUS

Test pulse number	Immunity test level	Functional status
1	III	D
2a	III	D
2b	III	D
3a/3b	III	D
4	III	D

Functional status D is where one or more functions of the ESA do not perform as designed during and after exposure and do not return to normal operation until exposure is removed and the ESA is reset by simple "operator/use" action.

## 8.3 BLOCK DIAGRAM OF TEST SETUP







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### 8.4 CLASSIFICATION OF FUNCTIONAL STATUS

**Class A:** all functions of a device/system perform as designed during and after exposure to disturbance.

**Class B:** all functions of a device/system perform as designed during exposure. However, one or more of them can go beyond specified tolerance. All functions return automatically to within normal limits after exposure is removed. Memory functions shall remain class A.

**Class C:** one or more functions of a device/system do not perform as designed during exposure but return automatically to normal operation after operation after exposure is removed.

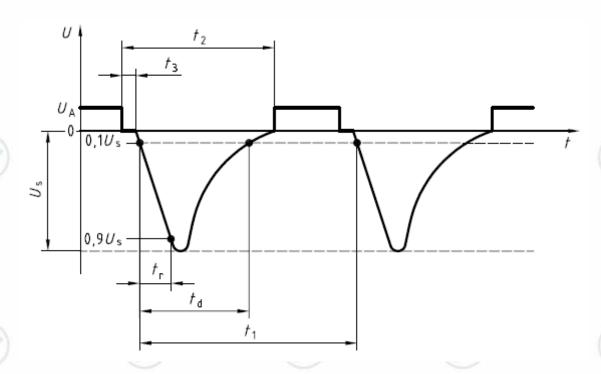
**Class D:** one or more functions of a device/system do not perform as designed during exposure and do not return to normal operation until exposure is removed and the device/system is reset by simple operator/use action.

**Class E:** one or more functions of a device/system do not perform as designed during and after exposure and can not be returned proper operation without repairing or replacing the device/system.

NOTE The word "function" in this context refers only to the function performed by the electronic system.

## 8.5 TEST PULSE AND PARAMETERS

## **8.5.1 TEST PULSE 1**











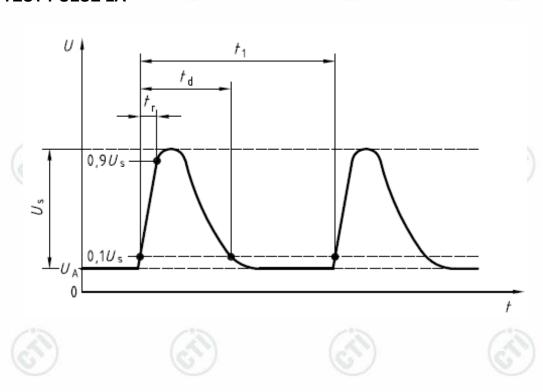
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Parameter	12 V system	24 V system			
$U_{\mathrm{s}}$	–75 V to – 100 V	– 450 V to – 600 V			
$R_{\rm i}$	10 Ω	50 Ω			
t <sub>d</sub>	2 ms	1 ms			
t <sub>r</sub>	1 <sub>-05</sub> μs	3 <sub>-1,5</sub> µs			
t <sub>1</sub> a	0,5 s to 5 s				
<i>t</i> <sub>2</sub>	200 ms				
t <sub>3</sub> b	< 10	0 μs			

 $<sup>^{</sup>m a}$   $t_{
m 1}$  shall be chosen such that the DUT is correctly initialized before the application of the next pulse.

# 8.5.2 TEST PULSE 2A













 $t_3$  is the smallest possible time necessary between the disconnection of the supply source and the application of the pulse.









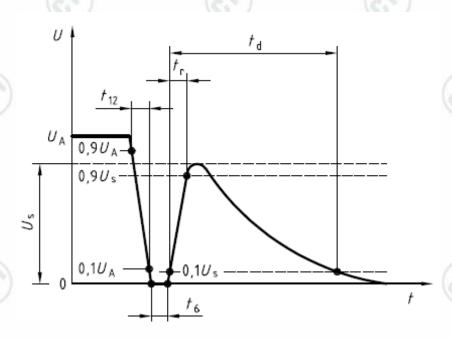
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Parameter	12 V system	24 V system	
$U_{\mathrm{s}}$	+ 37 V to + 50 V		
$R_{\rm i}$	2 Ω		
t <sub>d</sub>	0,05 ms		
t <sub>r</sub>	( 1 <sub>-0,5</sub> ) μs		
<sub>t1</sub> a	0,2 s to 5 s		

<sup>&</sup>lt;sup>a</sup> The repetition time  $t_1$  can be short, depending on the switching. The use of a short repetition time reduces the test time.

# 8.5.3 TEST PULSE 2B

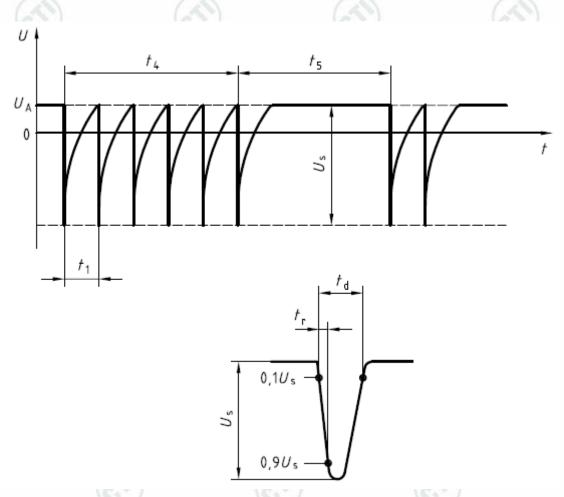


Parameter	12 V system	24 V system		
$U_{\mathtt{S}}$	10 V	20 V		
$R_{i}$	0 Ω to 0,05 Ω			
$t_{\sf d}$	0,2 s to 2 s			
t <sub>12</sub>	1 ms ± 0,5 ms			
t <sub>r</sub>	1 ms ± 0,5 ms			
<i>t</i> <sub>6</sub>	1 ms ± 0,5 ms			



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# 8.5.4 TEST PULSE 3A



	Parameter	12 V system	24 V system			
	$U_{\mathrm{s}}$	– 112 V to – 150 V	– 150 V to – 200 V			
767.07	$R_{\rm i}$	50 Ω				
	$t_{\sf d}$	<sup>0,1</sup> ) µs				
	t <sub>r</sub>	5 ns ± 1,5 ns				
	t <sub>1</sub>	100 μs				
	$t_4$	10	ms			
70	<i>t</i> <sub>5</sub>	90	ms			















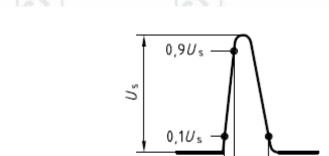


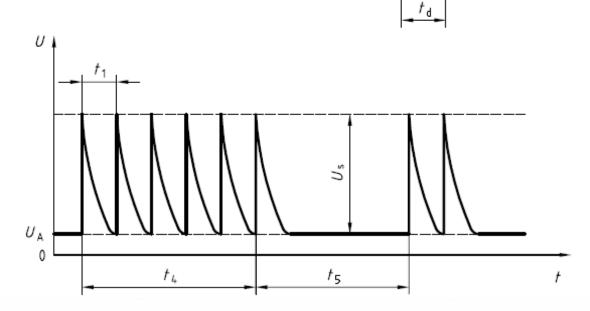


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# 8.5.5 TEST PULSE 3B





Parameter	12 V system	24 V system		
$U_{\mathrm{s}}$	+ 75 V to + 100 V	+ 150 V to + 200 V		
$R_{\rm i}$	50 Ω (0,1 <sup>+0,1</sup> <sub>0</sub> ) μs			
t <sub>d</sub>				
t <sub>r</sub>	5 ns ± 1,5 ns			
<i>t</i> <sub>1</sub>	100 μs			
t <sub>4</sub>	10 ms			
<i>t</i> <sub>5</sub>	90 ms			







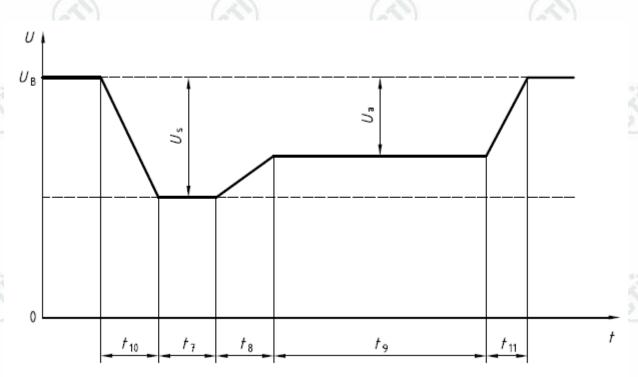








## 8.5.6 TEST PULSE 4



Parameter	12 V system	24 V system		
$U_{\mathtt{S}}$	– 6 V to – 7 V	– 12 V to – 16 V		
$U_{a}$	– 2,5 V to – 6 V with $ U_a  \le  U_S $	– 5 V to – 12 V with $ U_a  \le  U_S $		
$R_{i}$	0 Ω to 0,02 Ω			
t <sub>7</sub>	15 ms to 40 ms <sup>a</sup>	50 ms to 100 ms <sup>a</sup>		
t <sub>8</sub>	≤ 50 ms 0,5 s to 20 s <sup>a</sup>			
t <sub>9</sub>				
t <sub>10</sub>	5 ms	10 ms		
t <sub>11</sub>	5 ms to 100 ms <sup>b</sup>	10 ms to 100 ms <sup>c</sup>		

The value used should be agreed between the vehicle manufacturer and the equipment supplier to suit the proposed application.











 $t_{11} = 5$  ms is typical of the case when engine starts at the end of the cranking period, while  $t_{11} = 100$  ms is typical of the case when the engine does not start.

 $t_{11} = 10$  ms is typical of the case when engine starts at the end of the cranking period, while  $t_{11} = 100$  ms is typical of the case when the engine does not start.







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## 8.6 TEST RESULTS

Test Pulse	Test Voltage		Required	Test	Test
rest Puise	12V system	24V system	Level	Level	Result
1	-75V	-450V	D	B <sup>1</sup>	Pass
2a	+37V	+37V	D	Α	Pass
2b	+10V	+20V	D	C <sup>2</sup>	Pass
3a	-112V	-150V	D	Α	Pass
3b	+75V	+150V	D	Α	Pass
4	-6V	/	D	C <sup>2</sup>	Pass
4	1	-12V	D	Α	Pass

Remarks: 1. During test, the adapter will powered off and the displayer normal working. It will return automatically to normal operation after test.

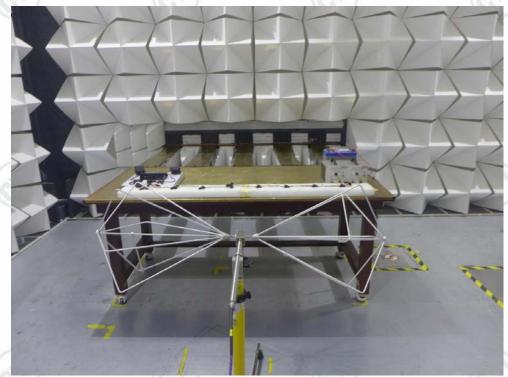
2. During test, the adapter will powered off and the displayer is black screen. It will return automatically to normal operation after test.



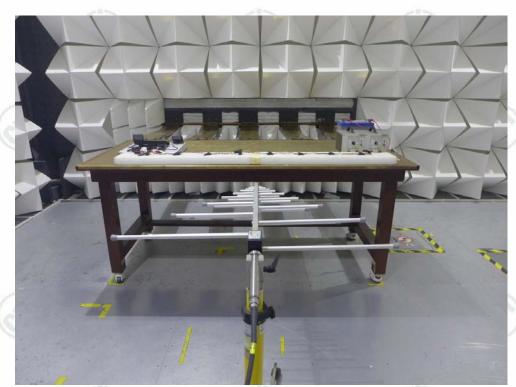


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# APPENDIX 1 PHOTOGRAPHS OF TEST SETUP



BROADBAND AND NARROWBAND RADIATED DISTURBANCES TEST SETUP (30MHZ-200MHZ)



BROADBAND AND NARROWBAND RADIATED DISTURBANCES TEST SETUP (200MHZ-1GHZ)









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**CONDUCTED TRANSIENT DISTURBANCES TEST SETUP** 



**CONDUCTED TRANSIENT IMMUNITY TEST SETUP** 



















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# **APPENDIX 2 PHOTOGRAPHS OF PRODUCT**



View of Product-1



View of Product-2













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View of Product-3



View of Product-4

# \*\*\* End of Report \*\*\*

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